

Notice of References Cited

Application/Control No.

10/822,023

Applicant(s)/Patent Under
Reexamination
CHURT ET AL.

Examiner

David Q. Nguyen

Art Unit

2617

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,195,018	02-2001	Ragle et al.	340/870.01
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NON-PATENT DOCUMENTS

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